Compression behavior of densified SiO₂ glass

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The compression behavior of fully densified SiO₂ glass has been measured up to 9 GPa at room temperature by using a diamond-anvil cell with a mixture of methanol-ethanol as a pressure medium. Optical-microscope observations clarify that there is remarkable agreement between the volume data on compression and decompression and therefore the glass behaves in an elastic manner. The compression curve can be expressed accurately enough by a Birch-Murnaghan equation of state with the zero-pressure bulk modulus $K_0 = 60.2$ GPa and its pressure derivative $K'_0 = 4$ (fixed). Extrapolating this equation of state to higher pressures, the density of the glass merges with that of ordinary glass (i.e., former ordinary glass compressed to high pressures) at about 13 GPa. X-ray diffraction and Raman scattering measurements show that the first sharp diffraction peak and the main Raman band of the glass also merge with those of ordinary glass at the similar pressure range. These results suggest that the compaction of interstitial voids dominates in compression mechanisms of densified SiO₂ glass, similar to the case for ordinary SiO₂ glass. Together with available information from the literature, it is presumed that the permanent densification of SiO₂ glass takes place between 9 and 13 GPa at room temperature. The behavior of SiO₂ glass in its intermediately densified states is also discussed.

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I. INTRODUCTION

High-pressure behavior of SiO₂ glass has been studied extensively because it has attracted considerable attention in various fields of physical sciences, such as high-pressure physics, noncrystalline physics, applied physics, geophysics, etc. In particular, numerous papers on permanent densification have been published since its discovery in the middle of the 20th century.¹ Various SiO₂ glasses having a density of up to about 20% larger than ordinary glass have so far been synthesized as a function of synthesis pressure and temperature and other parameters,^{2–4} suggesting the occurrence of continuous intermediate states between ordinary and fully densified glasses. High-pressure Brillouin⁵ and Raman^{6,7} scattering measurements, as well as molecular-dynamics simulations,⁸ have suggested that densified SiO₂ glass behaves in an elastic manner (i.e., as an amorphous polymorph).

In this study the compression curve of fully densified SiO₂ glass has been measured on both increasing and decreasing pressure to confirm that it behaves in an elastic manner. The measured compression curve is compared with available data in the literature, such as bulk moduli of fully densified SiO₂ glass obtained by elastic-wave-velocity measurements,^{9–11} compression curves of other amorphous and crystalline polymorphs of SiO₂, ^{12–18} and compression curves of intermediately densified SiO₂ glasses.^{10,19} X-ray diffraction and Raman scattering measurements have also been carried out to obtain structural information of fully densified SiO₂ glass under high pressure. Compression mechanisms, intermediate states, pressure conditions at which permanent densification takes place, and related topics are also discussed.

II. EXPERIMENT

Densified SiO₂ glass was synthesized by using a belt-type high-pressure apparatus²⁰ at National Institute for Materials

Science (Tsukuba, Japan). Synthetic ordinary SiO_2 glass in the form of a disk having a diameter of 6.0 mm and a thickness of 3.0 mm (or two disks having a diameter of 6.0 mm and a thickness of 1.5 mm) was used as a starting material. It was densified by heating to 873 K for 10 minutes at 10 GPa. Synthesis experiments were carried out several times. In all the experiments the recovered sample was broken into two large pieces (disks) and many small fragments. The density of large pieces was measured by the Archimedes method with distilled water as an immersion fluid. Small and thin fragments were confirmed to be the same as large pieces by Raman scattering measurements and used as a sample in diamondanvil experiments.

High-pressure *in-situ* experiments were carried out with a diamond-anvil cell.²¹ Measurements up to 9 GPa were carried out by using anvils having a 600- μ m flat culet with a tungsten-rhenium gasket and a methanol-ethanol pressure medium (a 4:1 mixture of methanol and ethanol). This pressure medium has been reported to remain hydrostatic within the pressure range of this study.^{22,23} The use of a helium pressure medium, which remains in a fluid state to higher pressures, was avoided because helium atoms may penetrate into interstitial voids of the sample.^{18,24} Pressure was determined by the rubyfluorescence method.²⁵ The culet of the anvil and the surface of the sample were not able to be focused simultaneously by an optical microscope throughout the experiments. This ensured that the sample, with an initial thickness of 60 μ m, did not bridge between the anvils and was not affected by deviatoric stresses.

The volume change (V/V_0) was determined by measuring the change in size of the sample in optical-microscope images.^{12,18,24} X-ray diffraction measurements were carried out by using an angle-dispersive method with 25 keV monochromatic x rays and an imaging plate detector at BL-18C of Photon Factory (Tsukuba, Japan). The exposure time was 8 and 5 hours for the sample and background, respectively. X-ray diffraction measurements at ambient pressure were carried out for a different sample (i.e., a large piece described previously). Raman scattering measurements were carried out by using the 488-nm line of an argon ion laser for excitation in a 150° light-scattering geometry and a $10 \times$ micro-optical spectrometer system consisting of a longpass filter, an imaging spectrometer, and a Peltier-cooled charge-coupled device. Raman spectra were corrected by measuring background.

III. RESULTS AND DISCUSSION

A. Compression curve

The pressure dependence of the density of densified SiO₂ glass is shown in Fig. 1. The zero-pressure density of the glass was measured to be $\rho_0 = 2.67 \text{ g/cm}^3$ by the Archimedes method. This value corresponds to a 21% increase in density (cf. 2.20 g/cm³ for ordinary SiO₂ glass), suggesting that the sample is fully densified. Errors in our zero-pressure density measurements may be as much as ± 0.05 g/cm³ and may not affect the discussion in this paper seriously. There is remarkable agreement between the data on compression and decompression, indicating that the sample behaves in an elastic manner. The zero-pressure bulk modulus was determined to be $K_0 = 60.2$ GPa, with its pressure derivative $K'_0 = 4$ (fixed), by fitting a Birch-Murnaghan equation of state²⁶ to the volume data. This value is in good agreement with $K_0 = 60-70$ GPa, obtained by elastic-wave-velocity measurements.9-11 The small difference may indicate that K'_0 is slightly smaller than 4, assuming that a difference between isothermal and adiabatic moduli can be ignored. It



FIG. 1. Pressure dependence of the density of fully densified SiO₂ glass at room temperature. The pressure dependence of the densities of ordinary SiO₂ glass (Refs. 12 and 16–18) and crystalline phases of SiO₂, quartz and coesite (Refs. 13 and 15), is also shown for comparison. Black and gray symbols represent the data on compression, and white symbols represent the data on decompression. All the data for SiO₂ glass were measured with a mixture of methanol-ethanol as a pressure medium except for the data shown as squares (measured without a pressure medium). The dashed-dotted line represents the equation of state of fully densified SiO₂ glass ($K_0 = 60.2$ GPa and $K'_0 = 4$).

has been reported that the compression curve of ordinary SiO_2 glass cannot be expressed accurately even by the fourth-order Birch-Murnaghan equation of state due to elastic softening.¹² It is worth pointing out that the compression curve of fully densified SiO₂ glass can be expressed accurately enough by the second-order Birch-Murnaghan equation of state.

The pressure dependence of the densities of ordinary SiO₂ glass^{12,16-18} and crystalline phases of SiO₂, quartz and coesite,^{13,15} is also shown in Fig. 1 for comparison. The data by Tsiok et al.14 for ordinary glass measured with a toroid-type high-pressure apparatus, which are not plotted to simplify the figure, agree very well with those with diamond-anvil cells.^{12,16-18} Although the compression curve of sixfold-coordinated SiO2 glass is located outside of Fig. 1, its zero-pressure parameters have been reported to be $\rho_0 = 3.88 \text{ g/cm}^3$, $K_0 = 190 \text{ GPa}$, and $K'_0 = 4.5^{17}$ It seems reasonable that densified SiO₂ glass exhibits an intermediate compressibility between those of ordinary and sixfold-coordinated SiO₂ glasses. Densified SiO₂ glass also exhibits an intermediate compressibility between quartz and coesite. Because glasses are normally more compressible than their crystalline counterparts,²⁷ densified SiO₂ glass may be a coesite-like amorphous polymorph.

Compression curves have so far been reported for intermediately densified SiO₂ glasses.^{10,19} The compression curves (and their extrapolation to higher pressures) of densified glasses with a different degree of densification in these reports appear to converge at around 8 GPa and 2.85 g/cm³, while the compression curve measured in this study does not pass through this region. In both El'kin et al.¹⁰ and Yokoyama et al.¹⁹ measurements were carried out on decreasing pressure at a constant temperature (475-800 K) for the glasses densified by heating at high pressures. Strictly, they are therefore not compression curves but decompression curves. If materials behave in an elastic manner, their compression and decompression curves are the same. However, this is not the case. It is very likely that the structure (i.e., the degree of densification) of the glasses may have changed with pressure. In El'kin et al.¹⁰ apparent compressibilities of the glasses are anomalously low at the highest-pressure range of their measurements, suggesting that structural transformations may have occurred at least in this pressure range. Moreover, in Yokoyama et al.,¹⁹ since the compression curves were estimated based on elastic-wave-velocity measurements, errors must increase with increasing pressure in addition to the possibility of structural transformations. Nevertheless, the bulk modulus tends to increase with increasing the degree of densification, if the compression curves, including that of this study, are compared in a relatively low-pressure range. Therefore, intermediately densified SiO₂ glasses may also behave in an elastic manner, at least in a low-pressure range at room temperature.

The compression curve of fully densified SiO₂ glass gets close to the density of former ordinary SiO₂ glass compressed to high pressures^{16,17} at about 13 GPa, as shown in Fig. 1. It is presumed that SiO₂ glass is fully densified by compression to this pressure (i.e., densification ends at this pressure). On the other hand, previous studies have clarified that densification begins at about 9 GPa.^{5–7,10,12,14,28,29} Therefore, it is presumed that at room temperature under hydrostatic conditions the densification of SiO₂ glass takes place at a

pressure interval between 9 and 13 GPa and then fully densified glass behaves as an amorphous polymorph up to the pressure where the structural transformation to sixfold-coordinated glass begins. The transformation to sixfold-coordinated glass has been reported to take place mainly at pressures between 20 and 35 GPa.³⁰ However, as shown in Fig. 1, the densities of SiO₂ glass measured by Sato and Funamori^{16,17} are already larger than the extrapolated density of fully densified glass below 20 GPa. This may indicate that the transformation to sixfold-coordinated glass already begins in part at this pressure range, as pointed out by Brazhkin.³¹ It is well known that nonhydrostatic stresses affect pressure conditions at which permanent densification takes place² (see the next section). Similarly, nonhydrostatic stresses may affect the transformation to sixfold-coordinated glass. Slight increases in coordination number can be seen below 20 GPa in Sato and Funamori³⁰ and Benmore *et al.*³²

B. X-ray diffraction and Raman scattering

The x-ray diffraction patterns and the pressure dependence of the position of the first sharp diffraction peak (FSDP) of densified SiO₂ glass are shown in Fig. 2, and the Raman spectra and the pressure dependence of the position of the main Raman band are shown in Fig. 3. Raman spectra measured at ambient pressure before compression and after decompression did not show any significant changes, supporting the result of the previous section that fully densified SiO₂ glass behaves in an elastic manner. However, intermediate-range structure (i.e., network structure consisting of SiO₄ tetrahedra) changes with pressure. The position of the FSDP and that of the main Raman band shift to higher Q and higher frequencies with increasing pressure, respectively. These shifts indicate that the compaction of interstitial voids plays a main role in reducing the bulk-sample volume under high pressure.^{18,24,33} Moreover, a so-called new peak^{17,18,30–36} appears in the x-ray diffraction pattern at 9 GPa. This pattern shows good agreement with that measured at 10 GPa by Sato and Funamori³⁰ (see Sato et al.³⁷ to compare the two patterns in detail), suggesting that short-range structure (i.e., SiO₄ tetrahedron) is not altered significantly by applying pressure in this pressure range.

The pressure dependence of the position of the FSDP [Fig. 2(b)] is quite similar to that of the density (Fig. 1). The data by Sato and Funamori¹⁶ and Benmore et al.³² measured on decreasing pressure from a pressure range of 30-40 GPa and those by Sato and Funamori³⁰ and Meade et al.³⁴ measured under conditions where the irradiation of intense white x rays has relaxed the structure may be assumed to be those for fully (or nearly fully) densified SiO₂ glass. This assumption is supported by the agreement between those studies and this study [Fig. 2(b)]. The position of the FSDP of fully densified SiO₂ glass is about 1.83 $Å^{-1}$ at ambient pressure. The FSDP positions of former ordinary and fully densified SiO₂ glasses become indistinguishable at the pressure range where the densities of these two glasses merge, i.e., at about 13 GPa. This result is consistent with in-situ x-ray diffraction observations of the densification of SiO₂ glass by heating at high pressures by Inamura *et al.*³³ On the other hand, although the pressure dependence of the position of the main Raman band [Fig. 3(b)] is also similar qualitatively, the positions of



FIG. 2. X-ray diffraction patterns and the pressure dependence of the FSDP position of fully densified SiO_2 glass at room temperature. The pattern of ordinary SiO_2 glass at ambient pressure is shown for comparison. The FSDP positions read from the patterns in (a) are shown as black symbols in (b). Gray and white symbols in (b) represent the literature data on compression and decompression, respectively, which were measured in experiments on ordinary SiO_2 glass as a starting material (Refs. 16, 30, and 32–35).

the two glasses seem to become indistinguishable at about 7 GPa, in contrast to the case of the FSDP position and the density. This discrepancy, however, can be ascribed to the fact that the D_1 band affects the determination of the main Raman band position [see Fig. 3(a)]. Therefore, it is presumed that the main Raman band positions of the two glasses become indistinguishable at essentially the same pressure range as in the case of the FSDP position and the density. These similarities strongly suggest that the compaction of interstitial voids dominates in compression mechanisms of densified SiO₂ glass, similar to the case for ordinary SiO₂ glass.

The position of the main Raman band of densified SiO₂ glass is shown as a function of synthesis pressure in Fig. 4. These data were compiled by reading peak positions from spectra in the literature.^{4–6,28,29,38–42} This figure shows that the peak position of fully densified SiO₂ glass is about 515 cm⁻¹ and confirms that the sample measured in this study is fully densified. The black symbols represent the data



FIG. 3. Raman spectra and the pressure dependence of the main Raman band position of fully densified SiO_2 glass at room temperature. The spectrum of ordinary SiO_2 glass at ambient pressure is shown for comparison. High-pressure *in-situ* Raman scattering measurements were carried out on decreasing pressure from 9 GPa. The main Raman band positions read from the spectra in (a) are shown as black symbols in (b). Gray and white symbols in (b) represent the literature data on compression and decompression, respectively, which were measured in experiments on ordinary SiO_2 glass as a starting material (Refs. 7, 28, 29, 40, and 48).

of densified glass synthesized at high temperatures of 800-1000 K, including that of this study. These data suggest that the densification takes place between 2 and 10 GPa at 800-1000 K. Trachenko et al.⁴³ reported that the density increase by heating (former) ordinary SiO₂ glass to 700-730 K is 1.2-1.5% at 10 GPa, based on both experiments and molecular-dynamics simulations. This value is significantly smaller than 4-5%, which is the density difference between (former) ordinary and fully densified glasses at 10 GPa obtained directly from Fig. 1. Therefore, heating to 700–730 K is insufficient to synthesize fully densified SiO₂ glass at 10 GPa. The white symbols represent the data of densified glass synthesized at room temperature under (truly or nearly) hydrostatic conditions and, in this case, the densification takes place at a narrow pressure interval between 9 and 13 GPa. This is in remarkable agreement with the previous discussion based on the pressure dependence of the density (Fig. 1), the FSDP position [Fig. 2(b)], and the



FIG. 4. Main Raman band position of densified SiO₂ glass at ambient conditions as a function of synthesis pressure. The position of ordinary SiO₂ glass is also shown for comparison. Black symbols represent the data of densified SiO₂ glass synthesized at high temperatures of 800–1000 K. Gray and white symbols represent the data of densified SiO₂ glass synthesized at room temperature under nonhydrostatic and hydrostatic conditions, respectively. It is well known that nonhydrostatic stresses not only hinder the densification at high pressures (as seen in this figure) but also promote it at low pressures, although Raman scattering measurements have not been reported. The data from the papers which show Raman spectra and details of synthetic conditions (Refs. 4–6, 28, 29, and 38–42) were complied by reading peak positions from the spectra.

main Raman band position [Fig. 3(b)]. The gray symbols represent the data of densified glass synthesized at room temperature under nonhydrostatic conditions and suggest that nonhydrostatic stresses significantly affect pressure conditions at which permanent densification takes place. It is well known that nonhydrostatic stresses not only hinder the densification at high pressures (above 10 GPa) but also promote it at low pressures² (although Raman scattering measurements have not been reported and thus no data are plotted in Fig. 4).

No significant differences are found between the glasses densified at room temperature and at high temperatures. This is consistent with the conclusion of Inamura *et al.*⁴⁴ On the other hand, the glass may have a slightly different structure when decompressed from higher pressures, i.e., above 20–35 GPa where the transformation to sixfold-coordinated glass takes place. As for the D₂ band, when densified at higher pressures, the position shifts slightly to higher frequencies and the intensity increases slightly relative to the main Raman band [e.g., compare Fig. 3(a) in this paper and Fig. 2 in Hemley *et al.*²⁸]. Moreover, the density and the FSDP position of the glass recovered from a pressure range of about 30 GPa have been reported to be 2.74 g/cm³ and 1.84 Å^{-1.16}

It is likely that the reading of positions of asymmetric peaks, such as the FSDP and the main Raman band, could differ systematically among papers. In order to make a quantitative comparison, it is important to present patterns or spectra in a paper (or in its supplementary information). In this paper all the data in Figs. 3(b) and 4, except for those of Vandembroucq *et al.*,⁷ were obtained by reading peak positions from spectra. Because the data of Vandembroucq *et al.*,⁷ at ambient pressure

in Fig. 3(b) most likely come from the same spectra for the data of Champagnon *et al.*⁶ in Fig. 4, the discrepancy is attributable to the difference in reading peak positions. Mukherjee *et al.*⁴⁵ reported the discovery of the first-order transition of SiO₂ glass with a density increase of about 20% at around 4 GPa and 950 K. It is worth pointing out that the x-ray diffraction pattern and the Raman spectrum of the high-density phase shown in their paper are completely different from those of densified SiO₂ glass shown in Figs. 2 and 3 in this paper.

C. Densification process

Vandembroucq et al.⁷ considered densification as plastic deformation by pressure and, from this view point, explained the phenomenon at room temperature very well. In their model the plastic deformation takes place when compressed beyond the elastic limit and the network structure of SiO₂ glass changes with pressure by rebonding SiO₄ tetrahedra. Vandembroucq *et al.*⁷ proposed that densified SiO₂ glass in a different state could be labeled with a maximum pressure applied to the glass as a fictive pressure. As discussed in the previous section, however, similar states can be achieved at a wide range of synthesis pressure due to the difference in temperature and/or nonhydrostaticity. Therefore, it is more appropriate to label simply with the zero-pressure density. According to this model, SiO₂ glass may behave as follows. In Fig. 1 the SiO₂ glass compressed to a pressure between 9 and 13 GPa is recovered from the pressure-density point to ambient pressure along its compression curve. The density of the glass recovered to ambient pressure is its zero-pressure density. When the glass is recompressed, it comes back to the original pressure-density point along the same compression curve. When the glass is compressed to a higher pressure between 9 and 13 GPa, further densification takes place and it behaves as a different glass having a new zero-pressure density. When the glass is compressed beyond 13 GPa, the densification is completed and it behaves as a fully densified glass with a zero-pressure density of about 2.67 g/cm^3 .

El'kin *et al.*¹⁰ considered densification as phase transformation. In their model intermediately densified glasses can be synthesized because of the kinetic barrier (or hysteresis) of transformation. While plastic deformation is irreversible, densified SiO₂ glass can revert back to ordinary SiO₂ glass at high temperatures, as summarized by El'kin *et al.*¹⁰ very well. At the same time, also in their model, the network structure of SiO₂ glass changes with pressure by rebonding SiO₄ tetrahedra, similar to the model by Vandembroucq *et al.*⁷ Molecular-dynamics simulations^{8,46} suggested that the rebonding causes modifications in the size distribution of the rings consisting of SiO₄ tetrahedra and therefore causes permanent densification. The transformation diagram proposed by El'kin *et al.*¹⁰ is consistent with Fig. 1, which shows that the permanent densification of SiO₂ glass takes place between 9 and 13 GPa at room temperature. In the transformation region ordinary glass is densified by heating. In some papers^{8,19} the volume decrease due to densification by heating because the volume of densified glass does not increase with decreasing temperature.

It may be useful to discuss intermediate states in more detail by considering densification as phase transformation. In the case of crystals the occurrence of continuous intermediate states is impossible, although an intermediate phase, having a structure different from both low- and high-pressure structures, can be formed. The kinetics usually causes the coexistence two phases, i.e., low- and high-pressure phases, with various ratios. In the case of liquids intermediate states are often described as a mixture of low- and high-pressure components, with the ratio of the two components changing with pressure.^{27,47} Moreover, intermediate states of liquids can be truly continuous. In both cases for liquids, however, an intermediate state does not behave in an elastic manner, because the kinetics usually does not matter and thus structure changes continuously with pressure. Therefore, the occurrence of continuous intermediate states and their elastic behavior may be characteristic of glass. The elastic behavior of the intermediate states has not yet been confirmed by experimental studies. Detailed high-pressure in-situ studies on the intermediate states will improve our understanding of the permanent densification.

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